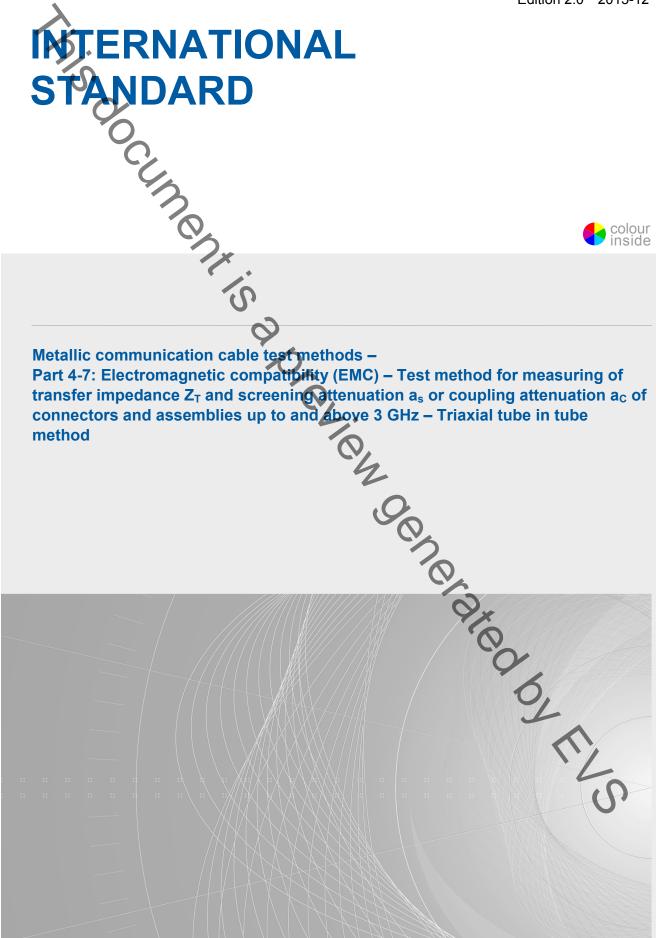




Edition 2.0 2015-12





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Metallic communication cable test methods -

Part 4-7: Electromagnetic compatibility (EMC) – Test method for measuring of transfer impedance  $Z_T$  and screening attenuation  $a_s$  or coupling attenuation  $a_c$  of connectors and assemblies up to and above 3 GHz – Triaxial tube in tube method

INTERNATIONAL ELECTROTECHNICAL COMMISSION



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## CONTENTS

FC	DREWC	)RD	5
		JCTION	
1		e	
2		native references	
3		and definitions	
4	•	ical background	
5	Princ	ciple of the test methods	
	5.1	General	. 10
	5.2	Transfer impedance	12
	5.3	Screening attenuation	12
	5.4	Coupling attenuation	
6	Test	procedure	. 13
	6.1	General	13
	6.2	Tube in tube procedure	13
	6.3	Tube in tube procedure	14
	6.4	Calibration procedure	
	6.5	Connection between extension tube and device under test	15
	6.6	Dynamic range respectively noise floor	15
	6.7	Impedance matching	16
	6.8	Influence of Adapters	16
7	Sam		
	7.1	Coaxial connector or device	17
	7.2	Balanced or multiconductor device Cable assembly	17
	7.3	Cable assembly	19
8	Meas	surement of transfer impedance	19
	8.1	General	19
	8.2	Principle block diagram of transfer impedance	19
	8.3	Measuring procedure – Influence of connecting cables	
	8.4	Measuring	20
	8.5	Evaluation of test results	
	8.6	Test report	20
9	Scre	ening attenuation	21
	9.1	General	21
	9.2	Impedance matching	21
	9.2.1		21
	9.2.2	Evaluation of test results with matched conditions	22
	9.2.3	Measuring with mismatch	22
	9.2.4	Evaluation of test results	22
	9.3	Test report	.23
10	Coup	bling attenuation	. 23
	10.1	Procedure	23
	10.2	Expression of results	
	10.3		
	10.4	Balunless procedure	
Ar	nnex A	(normative) Determination of the impedance of the inner circuit	26

Annex B (informative) Example of a self-made impedance matching adapter	.27
Annex C (informative) Measurements of the screening effectiveness of connectors	
and cable assemblies	
C.1 General	
C.2 Physical basics	
General coupling equation	
C.2.2 Coupling transfer function	
C.3 Triaxial test set-up C.3.1 General	
C.3.1 Measurement of cable assemblies	
C.3.3 Measurement of connectors	
C.4 Conclusion	
Annex D (informative) Influence of contact resistances	
Bibliography	
Figure 1 – Definition of $Z_{T}$	q
Figure 2 – Principle of the test set-up to measure transfer impedance and screening or	9
coupling attenuation of connectors with tube in tube	.11
Figure 3 – Principle of the test set-up to measure transfer impedance and screening attenuation of a cable assembly	. 14
Figure 4 – Principle set-up for verification test	. 16
Figure 5 – Preparation of balanced or multiconductor connectors	
Figure 6 – Test set-up (principle) for transfer impedance measurement according to	
test method B of IEC 62153-4-3	. 19
Figure 7 – Measuring the screening attenuation with tube in tube with impedance matching device	.21
Figure 8 – Measuring the coupling attenuation with tube in tube and balun	24
Figure 9 – Typical measurement of a connector of 0,04 m length with 1 m extension	
tube	.25
Figure 10 – Measuring the coupling attenuation with multiport VNA (balunless procedure is under consideration)	.25
Figure B.1 – Attenuation and return loss of a 50 $\Omega$ to 5 $\Omega$ impedance matching	
adapter, log scale	.27
Figure B.2 – Attenuation and return loss of a 50 $\Omega$ to 5 $\Omega$ impedance matching adapter, lin scale	.28
Figure C.1 – Equivalent circuit of coupled transmission lines	.30
Figure C.2 – Summing function S	.31
Figure C.3 – Calculated coupling transfer function ( $l = 1 \text{ m}$ ; $e_{r1} = 2,3$ ; $e_{r2} = 1, 2_F = 0$ )	
Figure C.4 – Triaxial set-up for the measurement of the screening attenuation $a_S$ and	.02
the transfer impedance Z <sub>T</sub>	. 33
	.35
Figure C.6 – Simulation of a cable assembly (linear scale)	.35
Figure C.7 – Triaxial set-up with extension tube for short cable assemblies	.36
Figure C.8 – Triaxial set-up with extension tube for connectors	.36
Figure C.9 – Simulation, logarithmic frequency scale	.37
Figure C.10 – Measurement, logarithmic frequency scale	.37
Figure C.11 – Simulation, linear frequency scale	.37

Figure C.12 – Measurement, linear frequency scale	
Figure C.13 – Simulation, logarithmic frequency scale	
Figure C.14 – simulation, linear frequency scale	
Figure D.1 – Contact resistances of the test set-up	
Figure D.2 – Equivalent circuit of the test set-up	
1	

- 4 -

Table 1 – IEO 62153,	Metallic communication cable test methods – Test procedures ວ1	
with triaxial test set-u	٥1	1

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### INTERNATIONAL ELECTROTECHNICAL COMMISSION

METALLIC COMMUNICATION CABLE TEST METHODS – Part 4-7: Electromagnetic compatibility (EMC) – Test method for measuring of transfer impedance  $Z_T$  and screening attenuation  $a_s$ or coupling attenuation  $a_c$  of connectors and assemblies up to and above 3 GHz – Triaxial tube in tube method

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International Standard IEC 62153-4-7 has been prepared by IEC technical committee 46: Cables, wires, waveguides, R.F. connectors, R.F. and microwave passive components and accessories.

This second edition cancels and replaces the first edition published in 2006. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

The document is revised and updated. The changes of the revised IEC 62153-4-3:2013, and IEC 62153-4-4:2015, are included.

Measurements can be achieved now with mismatch at the generator site, impedance matching devices are not necessary.

- 6 -

The text of this standard is based on the following documents:

FDIS	Report on voting
46/572/FDIS	46/585/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 62153 series, under the general title: *Metallic communication cable test methods*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
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### INTRODUCTION

The shielded screening attenuation test set-up according to IEC 62153-4-3 and IEC 62153-4-4 have been extended to take into account the particularities of electrically short elements like connectors and cable assemblies. Due to the concentric outer tube of the triaxial set-up, measurements are independent of irregularities on the circumference and outer electromagnetic fields.

With the use of an additional resonator tube (inner tube respectively tube in tube), a system is created where the screening effectiveness of an electrically short device is measured in realistic and controlled conditions. Also a lower cut off frequency for the transition between electrically short (transfer impedance  $Z_{T}$ ) and electrically long (screening attenuation  $a_{S}$ ) can be achieved.

A wide dynamic and frequency range can be applied to test even super screened connectors and assemblies with normal instrumentation from low frequencies up to the limit of defined transversal waves in the outer circuit at approximately 4 GHz.

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### **METALLIC COMMUNICATION CABLE TEST METHODS -**

Part 4-7: Electromagnetic compatibility (EMC) – Test method for measuring of transfer impedance  $Z_T$  and screening attenuation  $a_s$  or coupling attenuation  $a_c$  of connectors and assemblies up to and above 3 GHz – Triaxial tube in tube method

1 Scope

This triaxial method is suitable to determine the surface transfer impedance and/or screening attenuation and coupling attenuation of mated screened connectors (including the connection between cable and connector) and cable assemblies. This method could also be extended to determine the transfer impedance, coupling or screening attenuation of balanced or multipin connectors and multicore cable assemblies. For the measurement of transfer impedance and screening- or coupling attenuation, only one test set-up is needed.

### 2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC TS 62153-4-1, Metallic communication cable test methods – Part 4-1: Electromagnetic compatibility (EMC) – Introduction to electromagnetic screening measurements

IEC 62153-4-3, Metallic communication cable test methods – Part 4-3: Electromagnetic Compatibility (EMC) – Surface transfer impedance – Triaxial method

IEC 62153-4-4, Metallic communication cable test methods – Part 4-4: Electromagnetic compatibility (EMC) – Shielded screening attenuation, test method for measuring of the screening attenuation as up to and above 3 GHz

IEC 62153-4-15, Metallic communication cable test methods – Part 4-15: Electromagnetic compatibility (EMC) – Test method for measuring transfer impedance and screening attenuation – or coupling attenuation with Triaxial Cell

### 3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

# 3.1 surface transfer impedance

Ζ<sub>T</sub>

for an electrically short screen, quotient of the longitudinal voltage  $U_1$  induced to the inner circuit by the current  $I_2$  fed into the outer circuit or vice versa, see figure 1

Note 1 to entry: The surface transfer impedance is expressed in ohms.

Note 2 to entry: The value  $Z_T$  of an electrically short screen is expressed in ohms [ $\Omega$ ] or decibels in relation to 1  $\Omega$ .

Note 3 to entry: See Figure 1.